

Name of research institute or organization:

---

**iRoC Technologies, France**

Title of project:

---

Soft Error Test of electronic memory devices at high altitude

Project leader and team:

---

Anne-Lise Lhomme-Perrot, project leader  
SE Test Department

Project description:

---

Our experiment aims to test a memory device at high altitude in order to see its sensitivity towards the cosmic radiations. The test consists in writing data in the memories, waiting some time, and reading the memories by comparing their data with the written data. If the memory is sensitive towards the cosmic radiations, some errors will be obtained during the tests. The tests have been done from end of September to end of November.

Key words:

---

Cosmic rays, cosmic radiations, SSER, soft error test, semiconductor memory

Address:

---

iRoC Technologies  
4 place Rbert Schuman  
38000 Grenoble  
FRANCE

Contacts:

---

Anne-Lise Lhomme-Perrot  
Tel.: +33 438 120 763  
Fax: +33 438 129 615  
e-mail: anne-lise.lhomme-perrot@iroctech.com

